NEC

DATA SHEET

MOS FIELD EFFECT TRANSISTOR NP100P04PDG

SWITCHING **P-CHANNEL POWER MOSFET**

DESCRIPTION

The NP100P04PDG is P-channel MOS Field Effect Transistor designed for high current switching applications.

ORDERING INFORMATION <R>

PART NUMBER	LEAD PLATING	PACKING	PACKAGE	
NP100P04PDG-E1-AY Note		Tape 800 p/reel		
NP100P04PDG-E2-AY Note	00P04PDG-E2-AY Note Pure Sn (Tin)		TO-263 (MP-25ZP)	

Note Pb-free (This product does not contain Pb in external electrode.)

FEATURES

• Super low on-state resistance

 $R_{DS(on)1} = 3.5 \text{ m}\Omega \text{ MAX.}$ (Vgs = -10 V, ID = -50 A)

 $R_{DS(on)2} = 5.1 \text{ m}\Omega \text{ MAX.}$ (Vgs = -4.5 V, ID = -50 A)

• High current rating: ID(DC) = ∓100 A

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (VGs = 0 V)	VDSS	-40	V
Gate to Source Voltage (VDS = 0 V)	Vgss	∓20	V
Drain Current (DC) (Tc = 25°C)	D(DC)	∓100	А
Drain Current (pulse) ^{Note1}	D(pulse)	∓300	А
Total Power Dissipation (Tc = 25°C)	P T1	200	W
Total Power Dissipation (T _A = 25°C)	Pt2	1.8	W
Channel Temperature	Tch	175	°C
Storage Temperature	Tstg	–55 to +175	°C
Single Avalanche Current Note2	las	74	А
Single Avalanche Energy Note2	Eas	550	mJ

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Starting T_{ch} = 25°C, V_{DD} = -30 V, R_G = 25 Ω , V_{GS} = $-20 \rightarrow 0$ V

THERMAL RESISTANCE

Channel to Case Thermal Resistance	Rth(ch-C)	0.75	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

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(TO-263)

The mark <R> shows major revised points.

The revised points can be easily searched by copying an "<R>" in the PDF file and specifying it in the "Find what:" field.

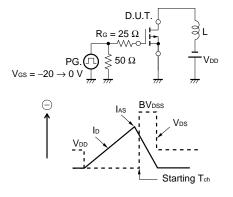
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = -40 V, V _{GS} = 0 V			-10	μA
Gate Leakage Current	Igss	V _{GS} = ∓20 V, V _{DS} = 0 V			∓100	nA
Gate to Source Threshold Voltage	V _{GS(th)}	V _{DS} = -10 V, I _D = -1 mA	-1.0	-1.6	-2.5	V
Forward Transfer Admittance Note	y _{fs}	V _{DS} = -10 V, I _D = -50 A	43	88		S
Drain to Source On-state Resistance Note	RDS(on)1	V _{GS} = −10 V, I _D = −50 A		2.8	3.5	mΩ
	RDS(on)2	V _{GS} = -4.5 V, I _D = -50 A		3.4	5.1	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V,		15100		pF
Output Capacitance	Coss	V _{GS} = 0 V,		2400		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		1130		pF
Turn-on Delay Time	td(on)	V_{DD} = -20 V, I _D = -45 A,		38		ns
Rise Time	tr	V _{GS} = -10 V,		30		ns
Turn-off Delay Time	td(off)	Rg = 0 Ω		300		ns
Fall Time	tr			100		ns
Total Gate Charge	QG	V _{DD} = -32 V,		320		nC
Gate to Source Charge	QGS	V _{GS} = -10 V,		37		nC
Gate to Drain Charge	Qgd	I⊳ = −100 A		85		nC
Body Diode Forward Voltage Note	V _{F(S-D)}	IF = -100 A, VGS = 0 V		0.91	1.5	V
Reverse Recovery Time	trr	I⊧ = −100 A, V₀s = 0 V,		70		ns
Reverse Recovery Charge	Qrr	di/dt = −100 A/ <i>µ</i> s		123		nC

ELECTRICAL CHARACTERISTICS (TA = 25°C)

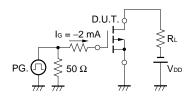
Note Pulsed test PW \leq 350 μ s, Duty Cycle \leq 2%

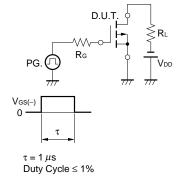
TEST CIRCUIT 1 AVALANCHE CAPABILITY

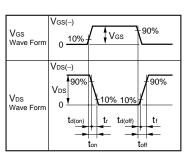
TEST CIRCUIT 2 SWITCHING TIME



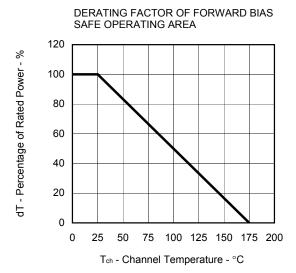
TEST CIRCUIT 3 GATE CHARGE



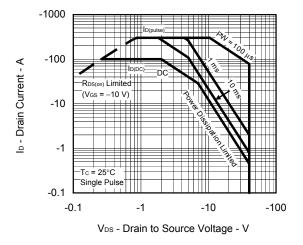


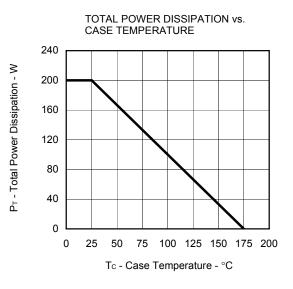


TYPICAL CHARACTERISTICS (TA = 25°C)

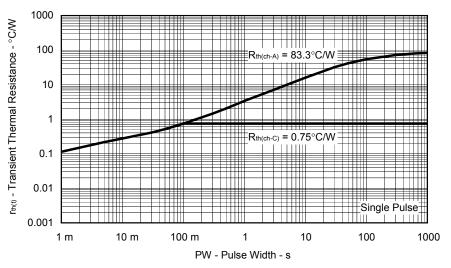






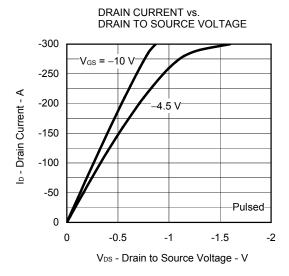


TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

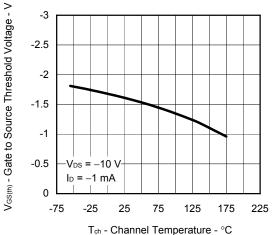


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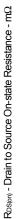


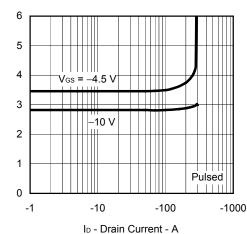




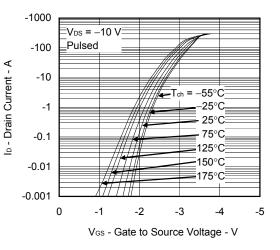


DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

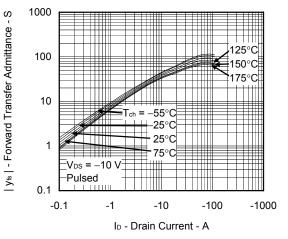




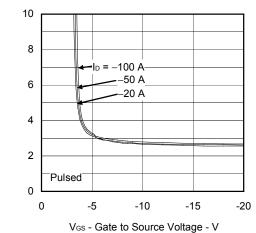




FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



 $R_{DS(on)}$ - Drain to Source On-state Resistance - $m\Omega$

-1

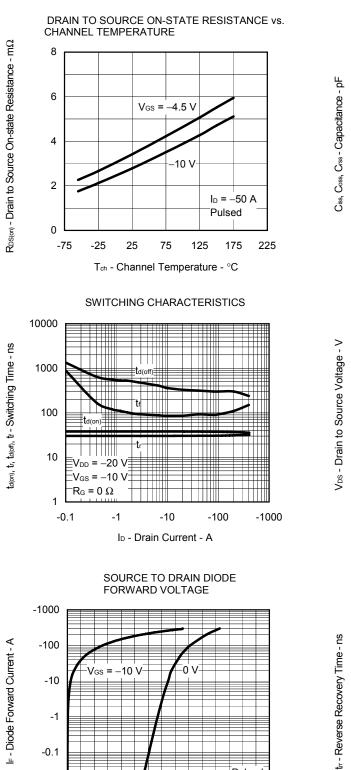
-0.1

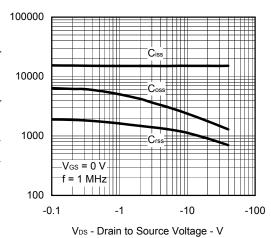
-0.01

0

0.5

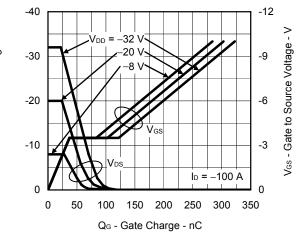
VF(S-D) - Source to Drain Voltage - V



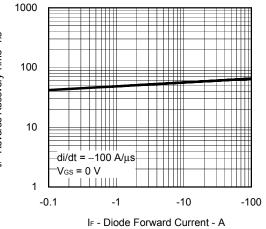


CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE

DYNAMIC INPUT/OUTPUT CHARACTERISTICS



REVERSE RECOVERY TIME vs. DIODE FORWARD CURRENT

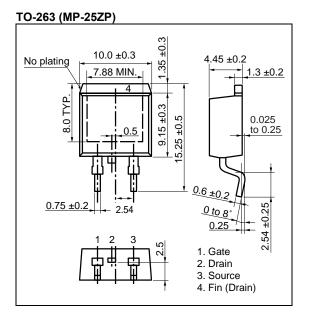


Pulsed

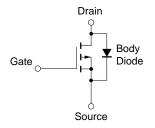
1.5

1

PACKAGE DRAWING (Unit: mm)



EQUIVALENT CIRCUIT



Remark Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

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